

OS QM-Tool

The Software for
better image quality



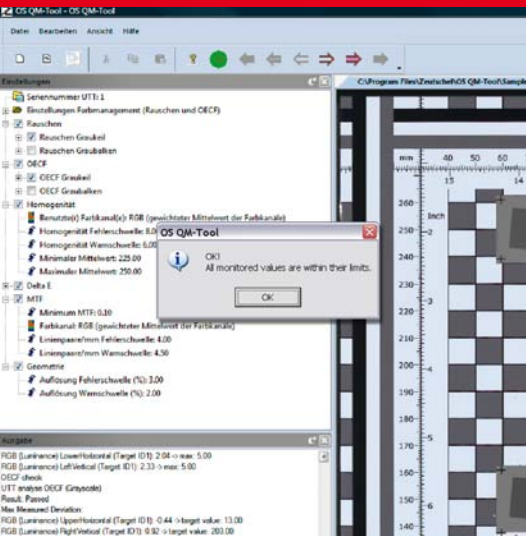
Better quality,
faster speed.

 **ZEUSCHEL**

The Future of the Past.

OS QM-Tool

The Software for
better image quality



Better results simply with the OS QM-Tool

Ensuring consistently high quality during the demanding mass digitization of library and archival collections thus far has been very labor-intensive and time-consuming and, consequently, expensive and error-prone. Furthermore, there still is no practice that would ensure the comparable application of national and international standards.

With its OS QM Tool, Zeutschel now offers software that makes it possible to analyze almost all relevant quality characteristics through the analysis of a single scan and to evaluate

these on the basis of selectable standards – and all that in only a few seconds. Moreover, the direct integration into the scanning software allows you to ensure the high quality already achieved during the scanning process.

By means of an innovative test chart, all relevant parameters can be captured with only one scan. A corresponding tool can analyze these parameters and determine within a few seconds whether or not an image meets the required standard. This makes it possible to automate quality control and to conduct it 'in-line' during the production process. It no longer has to run parallel to the production.

With regular use of the UTT, for example after 100 or 200 scans, the image quality of the digitized media can continuously be checked that way. This significantly reduces the risk of time-consuming repeat digitization of larger batches due to misalignments of the scanner.

This solution saves both, time and money during any mass digitization.



Zeutschel GmbH · Heerweg 2 · 72070 Tübingen
Tel.: +49 7071 9706-0 · Fax: +49 7071 9706-44
info@zeutschel.de · www.zeutschel.com

Advantages at a glance

- Analysis of all quality relevant parameters in one scan
- Easy to use
- Automatic work flow
- Detailed adjustable warning and error level
- Reporting
- ICC-conform processes
- Use of inexpensive targets (USS, DIN A3 to DIN A0)
- Automatic target recognition
- Quick batch processing

Technical Parameters

- MTF (modulation transfer function) according to ISO 16067
- Color reproduction ΔE (supported methods CIE 1976, CIE 1994, CIE 2000 etc.)
- Noise level according to ISO 12233
- OEFC (opto-electronic conversion function) according to ISO 14523
- Homogeneity
- Distorsion (resolution X and Y, channel registration, analysis of geometric aberration)
- WIN XP, VISTA and Windows 7 (32 and 64 bits)
- Target format DIN A3 to DIN A0

We reserve the right to make technical changes without notice.